Notice of References Cited Application/Control No. 10/614,195 Examiner Seokyun Moon Applicant(s)/Patent Under Reexamination HIRAYAMA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0130503	07-2004	Hamagishi et al.	345/006
	В	US-			
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FOREIGN PATENT DOCUMENTS

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